



NCCAVS CMP Users Group Fall Meeting

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Utilizing Advanced POU Filters for Two-Stage Filtration in Slurry Distribution Systems

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Agenda

Topic

- 1 About Entegris
- 2 Background on CMP Filtration
- 3 Experimental Procedure
- 4 Results/Discussion
- 5 Conclusions and Future Work

Entegris at a Glance

A world-class supplier of advanced materials and process solutions for the semiconductor, life sciences, and other high-tech industries



FOUNDED
1966



HEADQUARTERS
Billerica, MA



EMPLOYEES
~5,800



2020 REVENUE
\$1.9B



PATENTS
2,550+



Business Divisions

- Advanced Materials Handling (AMH)
- Microcontamination Control (MC)
- Specialty Chemicals & Engineered Materials (SCEM)

Our Mission

To help our customers improve their productivity, performance and technology by providing enhanced materials and process solutions for the most advanced manufacturing environments

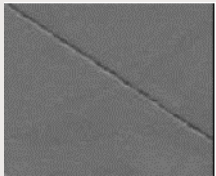
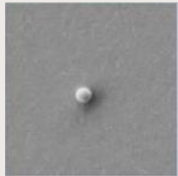

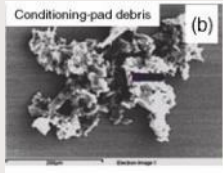


CMP Filtration

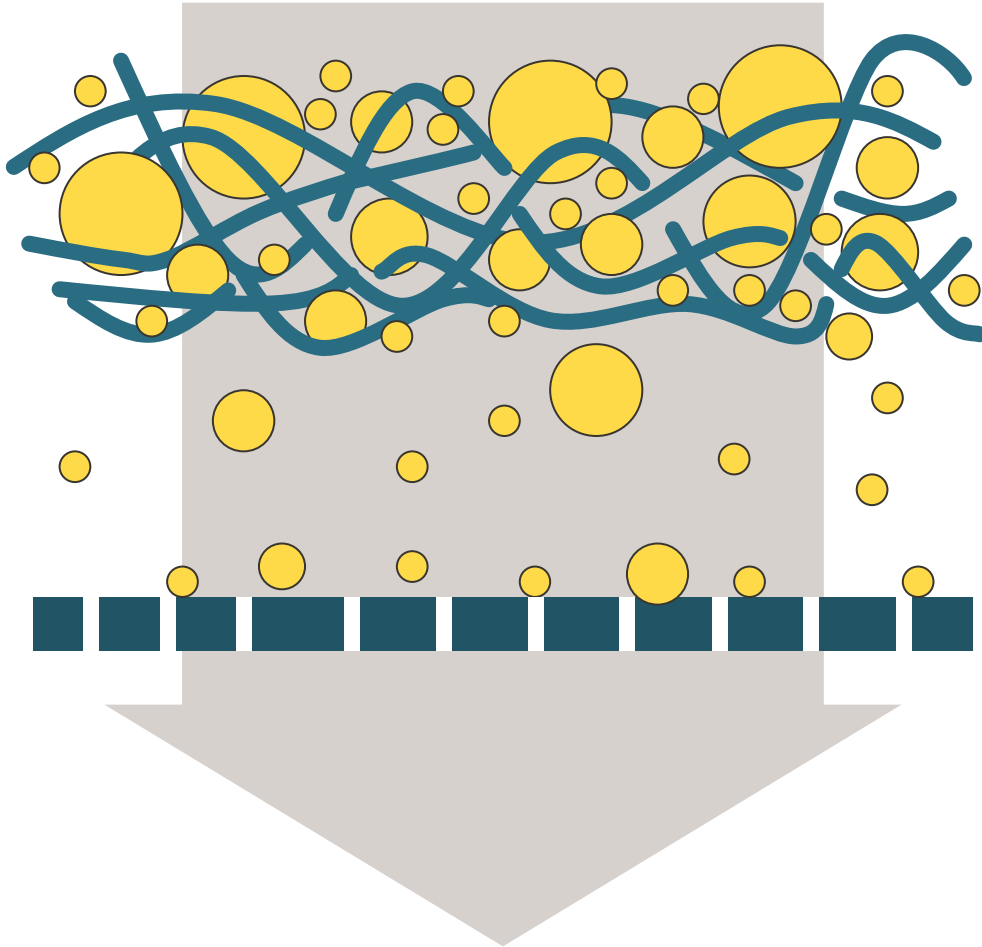


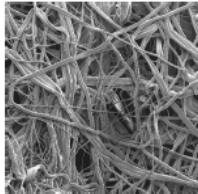
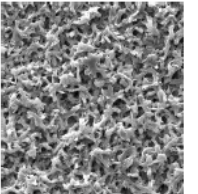
Role of Filtration in Addressing CMP Defects

- Agglomeration of slurry abrasive can lead to large particles or aggregates in the slurry during slurry distribution
- These particles can lead to scratches, which are one of the most important yield killers and require continuous improvement
- Filters facilitate scratch reduction, but scratches can come from various sources
- Filtration can address scratches and the particles that create scratches

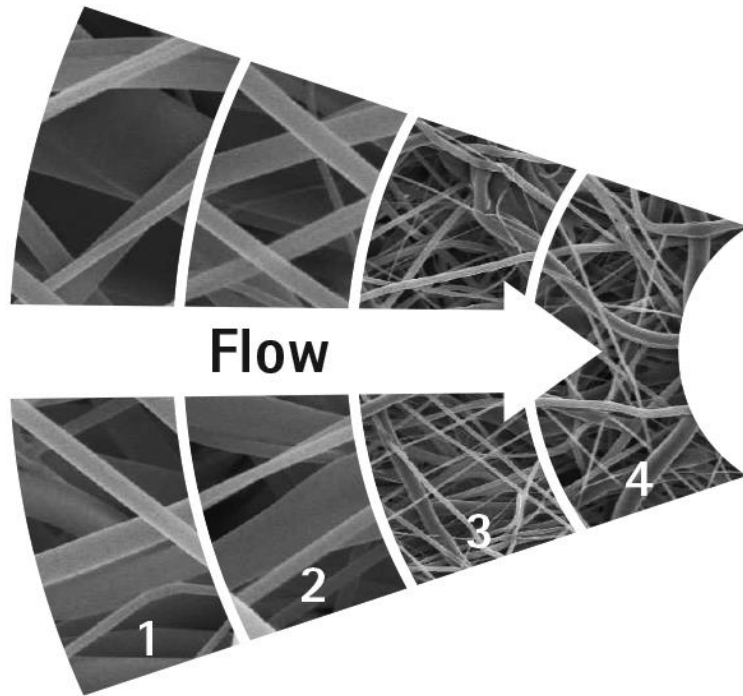
						
	Scratches	Particles	Pitting	Organics	Fall On	Others
Abrasive	FILTRATION	FILTRATION				
Slurry formation						Uniformity, topography, roughness
Post-clean						
Pad and conditioner						Type and lifetime
Facility						
Wafer						Roughness and uniformity

Depth vs. Membrane Filtration



	Depth	Membrane
Media		
Form	Interlock fibers	Continuous polymer sheet
FM holding capacity	Higher	Lower
Retention	Lower	Higher
Shedding	Can be high with pulsation	Low
Application	<ul style="list-style-type: none">• Pre-filtration• Slurry filtration• Chemical recirculation	Impurity removal from: <ul style="list-style-type: none">• Ultrapure chemicals• Photoresists• UPW

Slurry Filter Mechanisms for Large Particle Removal



- Slurry filters are traditionally depth-graded with polypropylene (PP) fibers
- Slurry filters are available in different retention ratings
- Nano-melt blown technology can reduce shear force during filtration, which has a strong impact on large particle counts (LPC)

Experimental Procedure



Test Setup and Parameters

Utilized two filter types for this testing

- 5" disposable (POU* 70 nm, 50 nm, 30 nm)
- 10" cartridge (CDS or global loop 0.1 μ m)

Constant parameters

- 2.7 LPM loop recirculation flow
- 300 mLPM POU single pass flow
- Acidic silica slurry (15 L per test)
- Test time ~2 hours
- Sampling time
 - Pre-test (baseline sample)
 - T1 (1 tank turn over)
 - T20 (20 tank turn overs)

*POU (Point of Use)



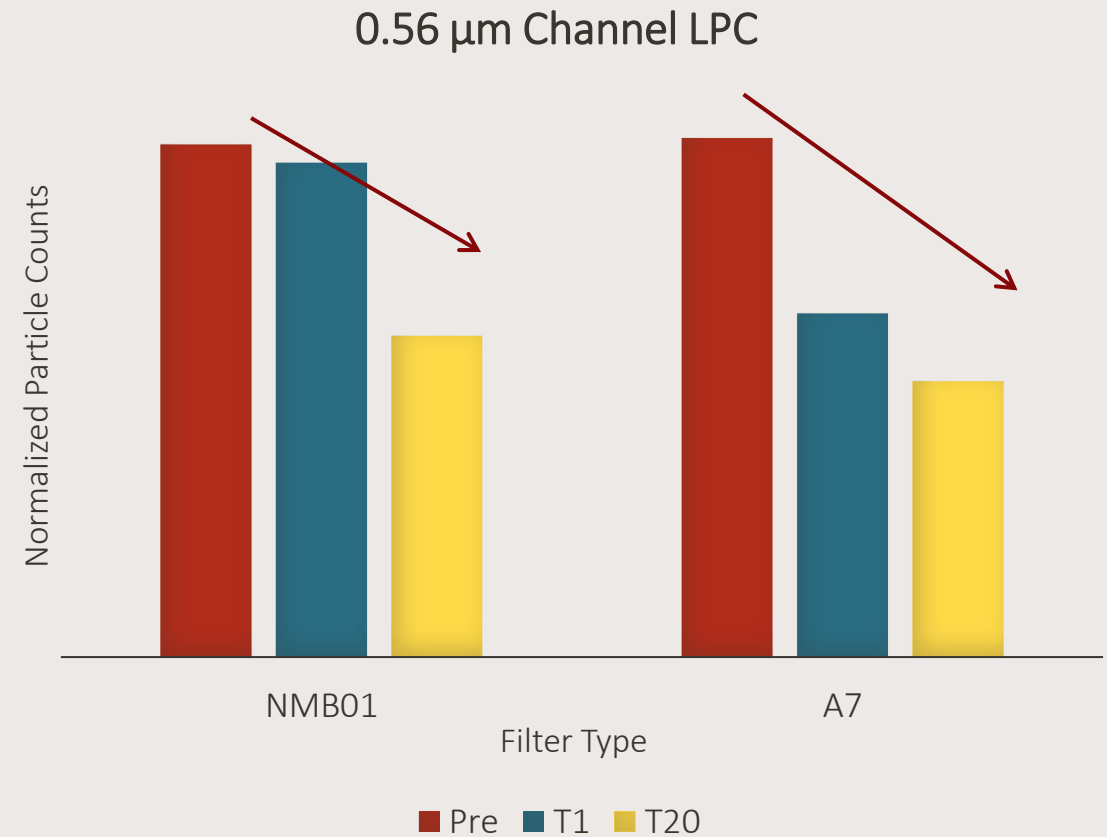
CMP Filter Test Stand

- Recirculation high-flow and low-flow test loops
- High-flow loop is Chemlock[®] compatible (Chemgard[™] housing shown)
- Two low-flow loops for Solaris[®] or Planarcap[®] style filters
- Single tank system
 - DIW or slurry compatible
 - Single process chemistry at a time
 - Constant stir mixer integrated with tank
 - Single pass to drain or recirculation flow paths configurable



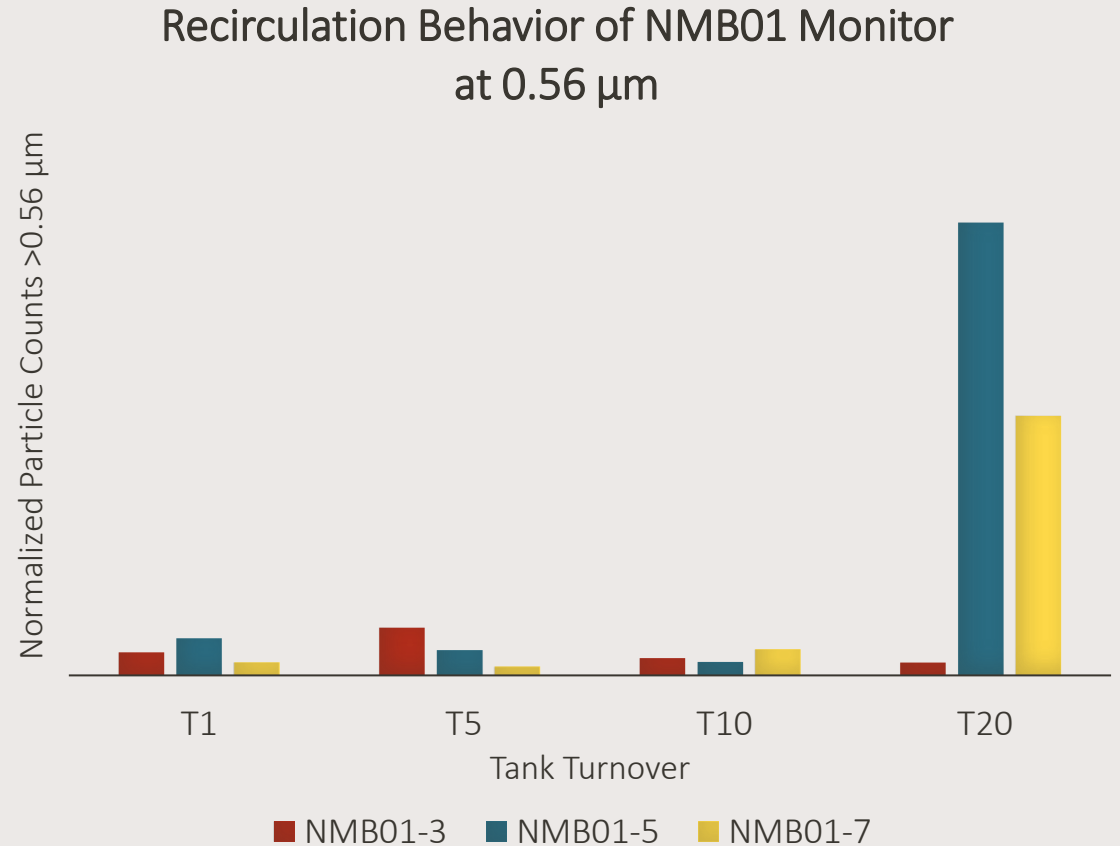
Example of Recirculating System Filtration Behavior

- Typical trend seen in recirculation systems
- Examples of recirculation with 2 different pore rating cartridge filters with batch-to-batch slurry variation
- Can be described as slurry clean-up or filter polishing of the slurry



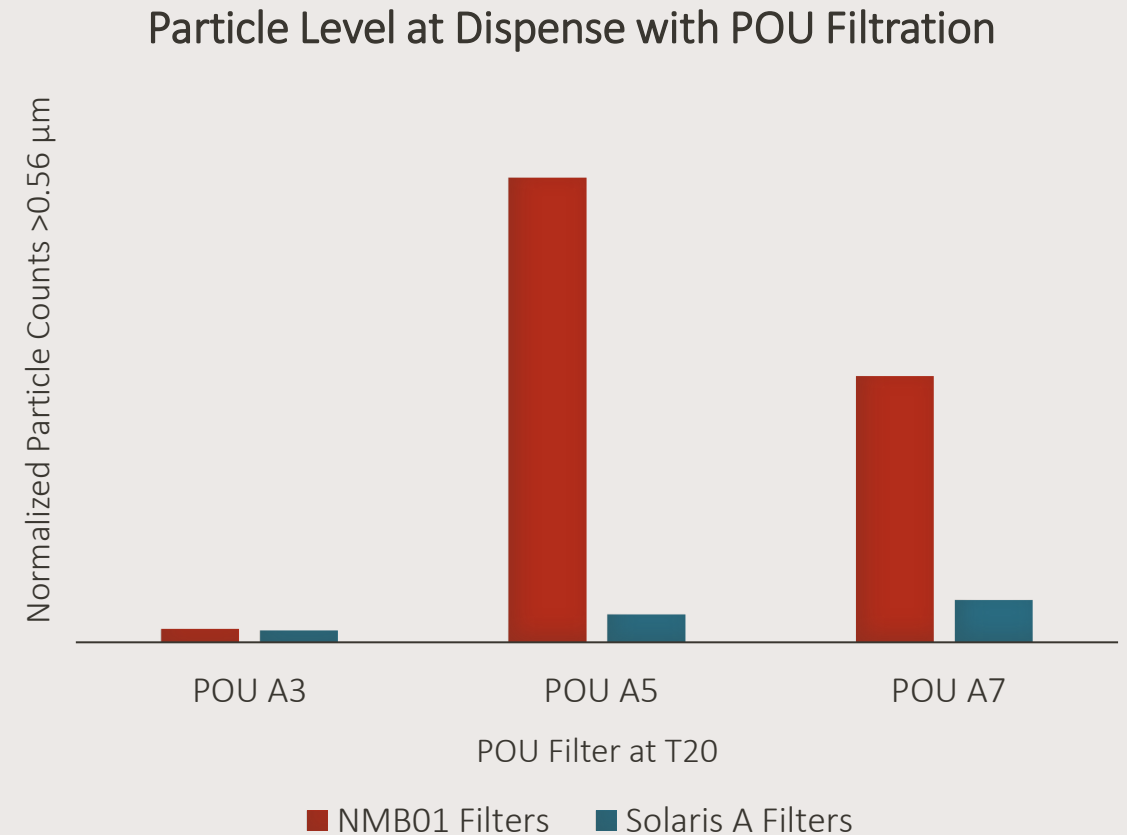
Experimental Results

- Typical scenario pictured on previous slide
- What if the loop filter doesn't perform optimally?
- Data shown here represents excursion at 20 tank turnovers
- How does one protect the wafer from such excursions?



Experimental Results

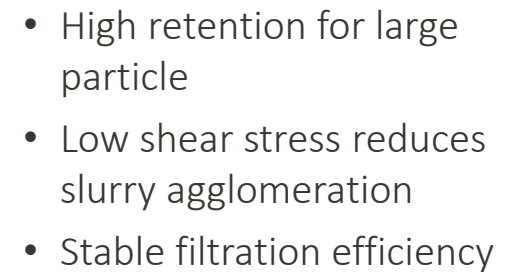
- As indicated above, Solaris 30 nm, 50 nm, and 70 nm filters were employed as POU filtration options for this testing
- Significant improvement of LPC counts shown with utilizing a POU/POD or guard filter
- Additional filtration step can safeguard the end-user process against premature loop filter excursions
 - In the case of the A3 testing, the loop filter did not experience an issue, but the POU filter still maintained a lower than loop level of particle counts



NMB A3 depth media features and benefits

- Entegris NMB technology offers low shear force filtration
- More nanofibers in both volume and thickness
- Optimized pore gradient

- Reducing slurry agglomeration
- Improve overall retention
- Stabilize retention under high-flow/
high-concentration condition



Conclusions

- CMP slurry filtration can aid in scratch reduction via large particle removal
- It is typical that loop filtration is employed as a safeguard against high LPC in a slurry batch
- In the event of batch-to-batch slurry variation, the loop filter will control most of the LPC
- If the variation induces a filter excursion, the only way to safeguard the process is a point-of-use filter
- Advanced filtration can also aid in the case of a stable process with a more open loop filter
- The POU filter will further polish the slurry to ensure stable performance on wafer



Thank you!
